

LIST OF RELATED CASES

Noted. sd 2/22/05

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent Appl. Publication No.</u>	<u>Inventor/ Applicant</u>
242419US2 DIV*	10/682,191	10/10/03	US 2004/0076449 A1	NAKAZATO, et al.
sd 263264US2	11/011,193	12/15/04		NAKAZATO, et al.

*Present Application; listed for information

GJM/sch

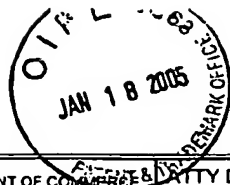
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242419US2DIV*	10/682,191	10/10/03	2004-0076449	NAKAZATO et al.
<i>SA</i> 261882US2	10/986,781	11/15/04		MATSUURA et al.

*Present Application; listed for information
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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

PRIORITY DOCKET NO.

242419US2DIV

SERIAL NO.

10/682,191

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasushi NAKAZATO, et al.

RCE FILED

Herewith

GROUP

2852

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
SL	AO	2000-035702	02/02/2000	JAPAN (with English Abstract)		X
SL	AP	03-275376	12/06/1991	JAPAN (with English Abstract)		X
SL	AQ	08-339110	12/24/1996	JAPAN (with English Abstract)		X
SL	AR	10-078737	03/24/1998	JAPAN (with English Abstract)		X
SL	AS	11-084883	03/30/1999	JAPAN (with English Abstract)		X
SL	AT	11-242370	09/07/1999	JAPAN (with English Abstract)		X
SL	AU	10-026864	01/27/1998	JAPAN (with English Abstract)		X
SL	AV	09-141972	06/03/1997	JAPAN (with English Abstract)		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

*S. Lee*Date Considered *2/22/05*

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242419US2DIV		SERIAL NO. 10/682,191	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasushi NAKAZATO, et al.			
				RCE FILED Herewith		GROUP 2852	
U.S. PATENT DOCUMENTS							
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	AM						
	AN						
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
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SL	AP	07-230197	08/29/1995	JAPAN (with English Abstract)			X
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>S. Lee</i>					Date Considered <i>2/22/05</i>		
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